

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10571862	IP, CHARLOTTE
	Examiner	Art Unit
	Young J Kim	1637

SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES

Search Notes	Date	Examiner
searched patent databases (USPT, USPPG, EPO, JPO, DERWENT, IBM-TDB)	2/15/2008	YJK
see enclosed for text-search strategy	2/15/2008	YJK
STIC assisted search of SEQ ID Numbers 1-4; (commercial, patent, and published databases)	2/15/2008	YJK

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner